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- Member of the Texas Instruments
 Widebus™ Family
- EPIC ™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

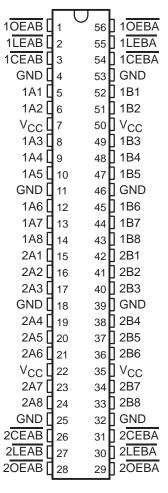
description

This 16-bit registered transceiver is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74ALVCH16543 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate latch-enable (LEAB or LEBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable (\overline{CEAB}) input must be <u>low to</u> enter data from A or to output data from B. If \overline{CEAB} is low and \overline{LEAB} is low, the A-to-B latches are transparent; a subsequent low-to-high transition of \overline{LEAB} puts the A latches in the storage mode. With \overline{CEAB} and \overline{OEAB} both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar, but requires using \overline{CEBA} , \overline{LEBA} , and \overline{OEBA} .

DGG OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16543 is characterized for operation from -40°C to 85°C.

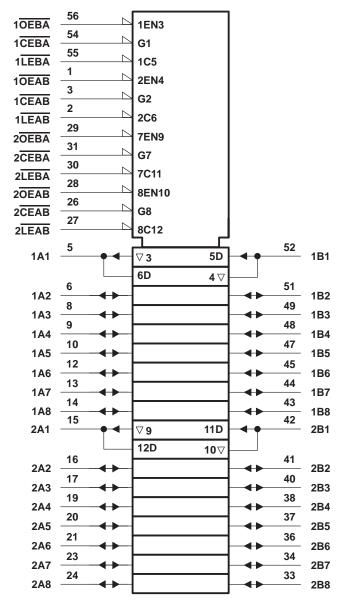


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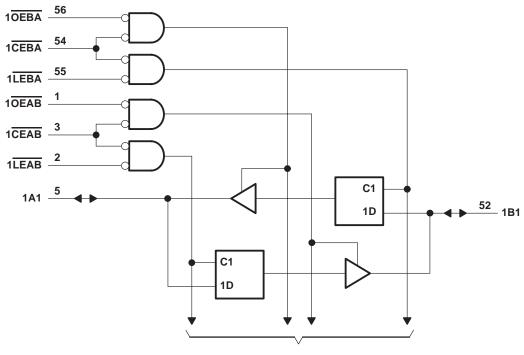
logic symbol†



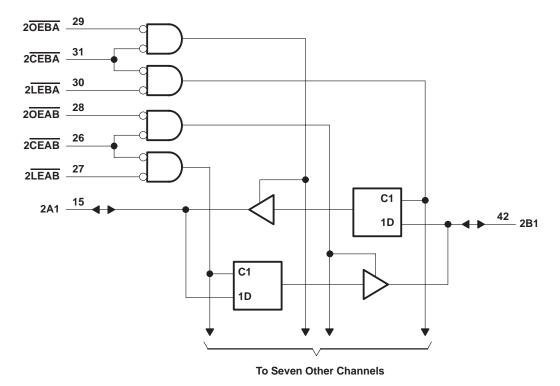
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)









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FUNCTION TABLE† (each 8-bit section)

	OUTPUT			
CEAB	LEAB	OEAB	Α	В
Н	Х	Х	Χ	Z
Х	Χ	Н	Χ	Z
L	Н	L	Χ	в ₀ ‡
L	L	L	L	L
L	L	L	Н	Н

[†] A-to-B data flow is shown; B-to-A flow control is the same except that it uses CEBA, LEBA, and OEBA.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage range, V _{CC}	0.5 V to 4.6 V
Input voltage range, V _I : Except I/O ports (see Note 1)	0.5 V to 4.6 V
I/O ports (see Notes 1 and 2)	–0.5 V to V_{CC} + 0.5 V
Output voltage range, V _O (see Notes 1 and 2)	
Input clamp current, $I_{ K }(V_1 < 0)$	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, IO	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DGG package	81°C/W
DL package	74°C/W
Storage temperature range, T _{stq}	65°C to 150°C

[§] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. This value is limited to 4.6 V maximum.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



[‡] Output level before the indicated steady-state input conditions were established

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT	
Vcc	Supply voltage		1.65	3.6	V	
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.65 × V _{CC}			
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V	
		voltage 1.65 vel input voltage $V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$ $0.65 \times V_{CC}$ vel input voltage $V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$ $1.7 \text{ V}_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$ vel input voltage $V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$ vel outge $V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$ voltage $V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$ vel output current $V_{CC} = 1.65 \text{ V V}$ vel output current $V_{CC} = 2.3 \text{ V V}$ vel output current $V_{CC} = 2.3 \text{ V V}$ vel output current $V_{CC} = 2.3 \text{ V V}$ vel output current $V_{CC} = 2.7 \text{ V V}$ vel output current $V_{CC} = 2.7 \text{ V V}$	2			
		V _{CC} = 1.65 V to 1.95 V		$0.35 \times V_{CC}$		
V _{IL}	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V	
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8		
٧ı	Input voltage		0	Vcc	V	
٧o	Output voltage		0	Vcc	V	
		V _{CC} = 1.65 V		-4		
	High-level output current	V _{CC} = 2.3 V		-12	mA	
ЮН		V _{CC} = 2.7 V		-12	IIIA	
		V _{CC} = 3 V	1.65 3.6 CC = 1.65 V to 1.95 V 0.65 × V _{CC} CC = 2.3 V to 2.7 V 1.7 CC = 2.7 V to 3.6 V 2 CC = 1.65 V to 1.95 V 0.35 × V _{CC} CC = 2.3 V to 2.7 V 0.7 CC = 2.7 V to 3.6 V 0.7 CC = 2.7 V to 3.6 V 0.8 0 V _{CC} CC = 1.65 V -4 CC = 2.3 V -12 CC = 2.7 V -12 CC = 3 V -24 CC = 2.3 V 12 CC = 2.7 V 12			
		V _{CC} = 1.65 V		4		
l	Low lovel output ourrent	V _{CC} = 2.3 V		12	mA	
lOL	Low-level output current	V _{CC} = 2.7 V		12		
		V _{CC} = 3 V		24		
Δt/Δν	Input transition rise or fall rate			10	ns/V	
T _A	Operating free-air temperature		-40	85	°C	

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



SN74ALVCH16543 16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PA	RAMETER	TEST C	ONDITIONS	Vcc	MIN	TYP [†]	MAX	UNIT
		I _{OH} = -100 μA		1.65 V to 3.6 V	V _{CC} -0.	.2		
$VOH \begin{tabular}{lllllllllllllllllllllllllllllllllll$	1.2							
	I _{OH} = -6 mA		2.3 V	2				
Vон				2.3 V	1.7			V
		I _{OH} = -12 mA		2.7 V	2.2			
				3 V	2.4			
		I _{OH} = -24 mA		3 V	2			
		I _{OL} = 100 μA		1.65 V to 3.6 V			0.2	
		I _{OL} = 4 mA		1.65 V			0.45	
\/O!		I _{OL} = 6 mA		2.3 V			0.4	V
VOL		lo 12 mA		2.3 V			0.7	V
		IOL = 12 IIIA		2.7 V			0.4	
		I _{OL} = 24 mA		3 V			0.55	
П		$V_I = V_{CC}$ or GND		3.6 V			±5	μΑ
		V _I = 0.58 V		1.65 V	25			
		V _I = 1.07 V		1.65 V	-25			
		V _I = 0.7 V		2.3 V	45			
I _I (hold)		V _I = 1.7 V		2.3 V	-45			μΑ
		V _I = 0.8 V		3 V	75			
		V _I = 2 V		3 V	-75			
		$V_{I} = 0 \text{ to } 3.6 \text{ V}^{\ddagger}$		3.6 V			±500	
loz§		$V_O = V_{CC}$ or GND		3.6 V			±10	μΑ
ICC		$V_I = V_{CC}$ or GND,	IO = 0	3.6 V			40	μΑ
∆lcc		One input at V _{CC} – 0.6 V,	Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μΑ
Ci	Control inputs	$V_I = V_{CC}$ or GND		3.3 V		3.5		pF
C _{io}	A or B ports	$V_O = V_{CC}$ or GND		3.3 V		8.5		pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			v _{CC} =	1.8 V	V _{CC} =	2.5 V 2 V	V _{CC} =	2.7 V	V _{CC} =	3.3 V 3 V	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t _W	t _w Pulse duration, LE or CE low		¶		3.3		3.3		3.3		ns
t _{su}	Setup time	Data before LE↑ or CE↑	¶		1.2		1.5		1.2		ns
th	Hold time	Data after LE↑ or CE↑	¶		1.2		0.8		1.3		ns

 $[\]P$ This information was not available at the time of publication.



[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. ‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] For I/O ports, the parameter IOZ includes the input leakage current.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM	FROM TO (INPUT) (OUTPUT)		V _{CC} =	2.5 V 2 V	VCC =	2.7 V	V _{CC} =	3.3 V 3 V	UNIT
	(INFOT) (OOTFOT)	TYP	MIN	MAX	MIN	MAX	MIN	MAX		
	A or B	B or A	†	1	5.1		4.8	1	4.3	ns
^t pd	LE	A or B	†	1	6.5		6.2	1.1	5	
t _{en}	CE	A or B	†	1	7.2		6.9	1	5.6	ns
t _{dis}	CE	A or B	†	1.3	6.1		6.2	1.5	5.1	ns
t _{en}	ŌĒ	A or B	†	1	6.8		6.3	1	5.3	ns
t _{dis}	ŌĒ	A or B	†	1	5.7		4.8	1.1	4.6	ns

[†] This information was not available at the time of publication.

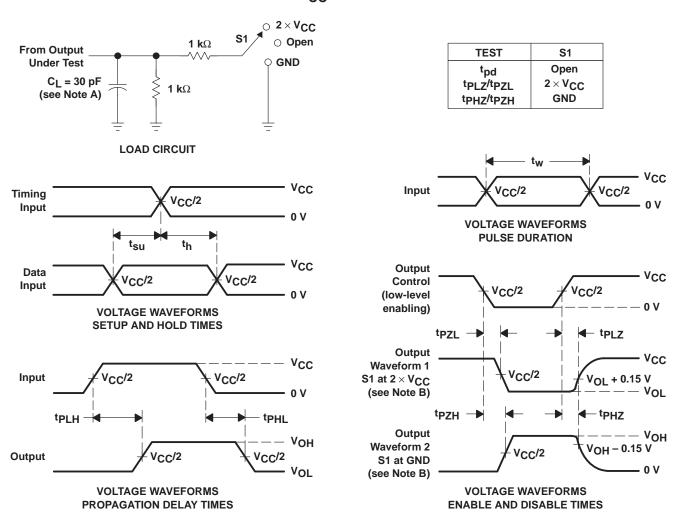
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8 V	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT	
	FARAWIETER		TEST CONDITIONS	TYP	TYP	TYP	ONIT
	Power dissipation	Outputs enabled	C ₁ = 50 pF. f = 10 MHz	†	54	64	pF
Cpd	capacitance	Outputs disabled	$C_L = 50 \text{ pF}, f = 10 \text{ MHz}$	†	6	7	рг

[†] This information was not available at the time of publication.

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PARAMETER MEASUREMENT INFORMATION V_{CC} = 1.8 V



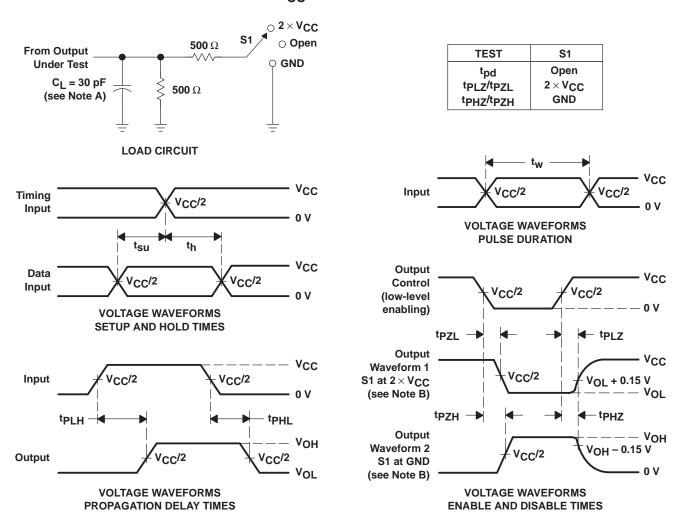
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzl and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$

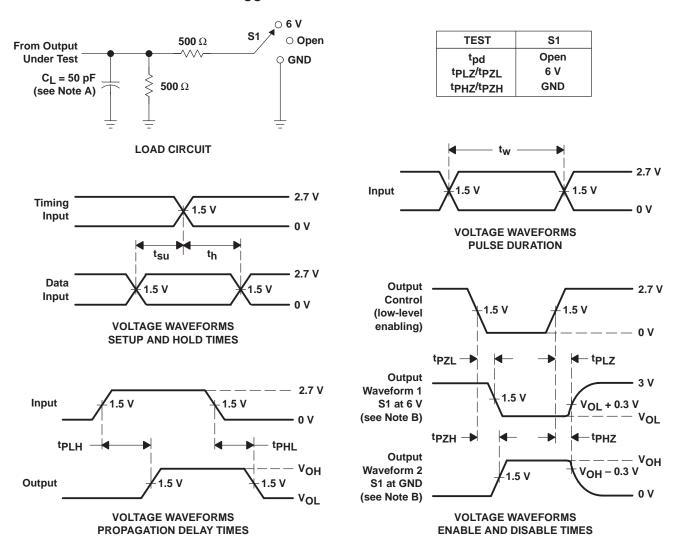


NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, $t_f \leq 2$ ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpl 7 and tpH7 are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.7 V AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_{O} = 50 \Omega$, $t_{f} \leq$ 2.5 ns, $t_{f} \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzi and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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